

Search Notes



Application/Control No.

10/543,092

Examiner

John S. Chu

Applicant(s)/Patent under
Reexamination

MIYAMATSU ET AL.

Art Unit

1752

SEARCHED

Class	Subclass	Date	Examiner
430	270.1	6/2007	JSC
430	905		
430	910		
430	922		
549	13		
549	29		
549	88		
549	90		
568	27		
568	28		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST SEARCH IN FILE	6/2007	JSC
INVENTOR SEARCH		
STRUCTURE SEARCH FROM EIC 1700		